

### 3.15

#### pn Junctions

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Reference: Pierret, chapter 5-6.

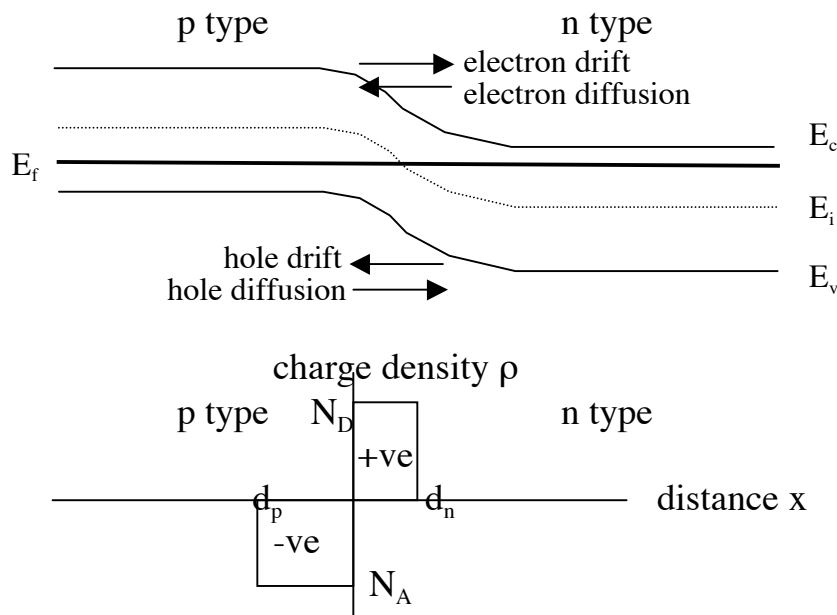
#### Unbiased (equilibrium) pn junction

Imagine an abrupt pn junction. The p side has a high hole concentration and the n side has a high electron concentration.

There is immediate **diffusion** of the carriers down the concentration gradient.

This leaves a space charge due to the ionized dopants. The resulting electric field leads to **drift** of carriers *in the opposite direction* compared to the diffusion flux.

**At equilibrium the drift and diffusion currents are balanced.**



Gauss' law  $\mathbf{E} = 1/\epsilon_0\epsilon_r \int \rho(x) dx$       where  $\rho = e(p - n + N_D - N_A)$

Energy (i.e. position of energy bands) =  $eV$ ; can be found from voltage vs distance; calculate from  $\mathbf{E} = -dV/dx$

Depletion region width  $d = d_p + d_n$  (some books use  $d = x_p + x_n$ )

Built-in voltage  $V_o$ : from earlier,

$$n = n_i \exp((E_f - E_i)/kT)$$

$$p = n_i \exp (E_i - E_f)/kT$$

The Fermi level is flat across the junction:

$$eV_o = (E_f - E_i)_{n\text{-type}} - (E_f - E_i)_{p\text{-type}} \\ = kT/e \ln (n_n/n_p) \text{ or } kT/e \ln (N_A N_D/n_i^2)$$

Using the depletion approximation  $\rho = -N_A e$  in the p-type and  $N_D e$  in the n-type:

$$E = N_A e d_p / \epsilon_o \epsilon_r = N_D e d_p / \epsilon_o \epsilon_r \quad \text{at } x = 0 \\ V_o = (e / 2 \epsilon_o \epsilon_r) (N_D d_n^2 + N_A d_p^2) \\ d_n = \sqrt{\{(2 \epsilon_o \epsilon_r V_o / e) (N_A / (N_D (N_D + N_A)))\}} \\ d = d_p + d_n = \sqrt{\{(2 \epsilon_o \epsilon_r V_o / e) (N_D + N_A) / N_A N_D\}}$$

Biased pn junction (apply voltage  $V_A$ )

**Forward bias raises the n-side energy levels** (or lowers the p-side)

by applying -ve to the n-side (or +ve to p-side)

This **reduces** the voltage barrier. The quasi-Fermi level is higher on the n-side.

The diffusion term changes because the number of carriers eligible to diffuse increases exponentially.

The drift term does not change.

Outside the depletion region there is a net diffusion current.

**Reverse bias lowers the n-side energy levels.**

Diffusion is reduced; drift is unchanged. Only a small reverse current flows.

Reverse bias increases the depletion width

$$d = \sqrt{\{(2 \epsilon_o \epsilon_r (V_o + V_A) / e) (N_D + N_A) / N_A N_D\}}$$

The ideal diode equation

In forward bias the diffusion flux increases because more carriers are able to diffuse. This comes from the Fermi function. When  $E_f$  is away from the band edge,

$$f(E) = 1 / \{1 + \exp (E - E_f) / kT\} \sim \exp -(E - E_f) / kT$$

If we shift the energy levels by  $V_A$ , we change the available number of carriers by a factor

$$\{\exp -(e(V_o - V_A) - E_f) / kT\} / \{\exp -(eV_o - E_f) / kT\} \\ = \exp eV_A / kT$$

Therefore diffusion flux  $J_{\text{diff}} = J_o \exp eV_A/kT$

To evaluate  $J_o$ , we know that  $J_o = -J_{\text{drift}} = J_{\text{diff}}$  at  $V_A = 0$ .

Consider an asymmetric junction with  $N_A \gg N_D$ , then the current is mainly holes, and their concentration decays in the n-type material (outside the depletion region) over a distance  $\lambda_p = \sqrt{\tau_p D_p}$ . The diffusion current

$$J_{\text{diff}} = eD_p \nabla p = eD_p (p_{n(x=0)} - p_{\text{no}}) / \lambda_p \quad (\text{where } p_{\text{no}} = n_i^2 / N_D)$$

$$\sim eD_p (p_{n(x=0)}) / \lambda_p$$

$$p_n = p_p \exp -eV_o/kT \text{ (unbiased)}$$

$$\text{and } p_n = p_p \exp -e(V_o - V_A)/kT \text{ (forward biased)}$$

$$\text{so } p_n = p_{\text{no}} \exp -eV_A/kT$$

Hence  $J_{\text{diff}} = \{eD_p n_i^2 / N_D \lambda_p\} \exp -eV_A/kT = J_o \exp eV_A/kT$

Include both electron and hole terms:  $J_o = en_i^2 \{D_p / N_D \lambda_p + D_n / N_A \lambda_n\}$

Also,  $J_{\text{drift}} = J_o$  gives an expression for  $J_{\text{drift}}$

The ideal diode equation is then

$$J = J_{\text{diff}} + J_{\text{drift}} = J_o \{ \exp eV_A/kT - 1 \}$$

What happens in reverse bias? The current reaches a reverse saturation value of  $J_o$  ( $\sim 10^{-12}$  A  $\text{cm}^{-2}$  in Si)

All minority carriers reaching the depletion region are sucked across (i.e. the junction 'collects' minority carriers). There is no diffusion flux across the depletion region. There is a diffusion flux outside the depletion region that supplies minority carriers to the junction: its value is just  $-en_i^2 \{ p_{\text{no}} D_p / \lambda_p + n_{\text{po}} D_n / \lambda_n \} = -J_o$ .

**Reverse bias pn junction collects minority carriers**

**Forward bias pn junction injects minority carriers**

Non-idealities:

- a) Reverse bias Zener breakdown, where carriers tunnel through a narrow depletion width
- b) Avalanche diode, where impact ionization generates more carriers in the depletion region.